STATEMENT UNDER 37 CFR 1.97(e) ACCOMPANYING INFORMATION DISCLOSURE STATEMENT

Docket No. 14846-36

In Re Application Of: Aura Yanavi

Serial No.

Filing Date

Examiner

Group Art Unit

TBD

November 20, 2003

TBD

TBD

Invention:

Methods and Systems For Predicting Software Defects In An Upcoming Software Release

TO THE COMMISSIONER FOR PATENTS:

This is a statement under the provisions of 37 CFR 1.97(e) in the above-identified application.

Check applicable statement herebelow:

Statement Under 37 CFR 1.97(e)(1)

☐ Each item of information contained in the accompanying Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the Information Disclosure Statement.

Statement Under 37 CFR 1.97(e)(2)

No item of information contained in the accompanying Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application, and, to the knowledge of the undersigned person, after making reasonable inquiry, no item of information contained in the accompanying Information Disclosure Statement was known to any individual designated in 37 CFR 1.56(c) more than three months prior to the filing of the Information Disclosure Statement.

Dy D. Nora

Dated: November 20, 2003

George Morgan, (Reg. No. 46,505) LOWENSTEIN SANDLER PC 65 Livingston Avenue Roseland, New Jersey 07068 973-597-2500

Certificate of Mailing by First Class Mail

I certify that this document is being deposited on

November 20, 2003 with the U.S. Postal Service as first class mail under 37 C.F.R. 1.8 and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

Kelly Billingsley

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INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

SERIAL NO. ATTY DOCKET NO. 14846-36 **TBA**

Methods and	Systems Fo	r Predicting	Software	Defects

FILING GROUP

November 20, 2003 **TBA**

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	US 6,073,107	06/06/00	Minkiewicz et al.				
	US 6,477,471	11/05/02	Hedstrom et al.				
	US 6,546,506	04/08/03	Lewis				
	US 5,446,895	08/29/95	White et al.				
	US 5,655,074	08/05/97	Rauscher				
	US 5,758,061	05/26/98	Plum				
	US 5,903,897	05/11/99	Carrier III et al.				
	US 5,960,196	09/28/99	Carrier III et al.				
	US 6,363,524	03/26/02	Loy				
	US 6,405,364	06/11/02	Bowman-Amuah				
	US 6,513,154	01/28/03	Porterfield				
	FOREIGN PATENT DOCUMENTS						

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
		22		05.00		YES	NO
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(Including Author, Title, Date, Pertinent Pages, Etc.) OTHER DOCUMENTS

Hudepohl, J.P., et al., "Integrating Metrics and Models For Software Risk Assessment," p. 93, The Seventh International Symposium on Software Reliability Engineering (ISSRE'96) October 30-November 02, 1996, White Plains, NY (Abstract)

Levendel, Y., "Reliability Analysis of Large Software Systems: Defect Data Modeling," pp. 141-152, IEEE Transactions on Software Engineering (Abstract)

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

INFORMATION DISCLOSURE CITATION

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ATTY DOCKET NO.	SERIAL NO.
14846-36	ТВА
14040-30	IDA
Methods and Systems For	Predicting Software Defects

		=	November 20,			ТВА	
		U	.S. PATENT DOCUMENTS				
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
	US 6,519,763	02/11/03	Kaufer et al.				
	US 6,601,017	07/29/03	Kennedy et al.				
	US 6,601,018	07/29/03	Logan				
	US 6,601,233	07/29/03	Underwood				
	US 6,626,953	09/30/03	Johndrew et al.				
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	US 2003/0033586	02/13/03	Lawler				
	US 2003/0188290	10/02/03	Corral				
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	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSL	
						YES	NO
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	OTHER DOCUME	ENTS (Includi	ng Author, Title, Date, Pertinen	t Pages, Etc.)		<u> </u>	
	Yu, T.J., et al., "An An Engineering (Abstract)	alysis of Several	Software Defect Models," pp. 1261	-1270, IEEE Tra	ansactions on S	Software	
	Wohlin, C., et al., "Und Program Comprehension	erstanding the S on (IWPC'00), Ju	ources of Software Defects: A Filter une 10-11, 2000 (Abstract)	ring Apporach,:	8th Internation	onal Worksh	op on
EXAMINER			DATE CONSIDERED				

Form PTO-A820 (also form PTO-1449)

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ATTY DOCKET NO. SERIAL NO. 14846-36 **TBA** INFORMATION DISCLOSURE CITATION Methods and Systems For Predicting Software Defects...... (Use several sheets if necessary) FILING GROUP November 20, 2003 **TBA U.S. PATENT DOCUMENTS** *EXAMINER FILING DATE DOCUMENT NUMBER DATE NAME CLASS SUBCLASS INITIAL IF APPROPRIATE US 2003/0196190 10/16/03 Ruffolo et al. **FOREIGN PATENT DOCUMENTS** TRANSLATION DOCUMENT NUMBER DATE COUNTRY CLASS SUBCLASS YE\$ NO OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) McConnell, S., "Gauging Software Readiness with Defect Tracking," IEEE Software, pp. 135-136 (Abstract)

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Mohapatra, S., et al., "Defect Prevention through Defect Prediction: A Case Study at Infosys," Utkal University, IEEE International Conference on Softwars Maintenance (ICSM'01), November 7-9, 2001, p. 260 (Abstract)

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

ATTY DOCKET NO. SERIAL NO. 14846-36 **TBA** INFORMATION DISCLOSURE CITATION Methods and Systems For Predicting Software Defects...... (Use several sheets if necessary) FILING GROUP November 20, 2003 **TBA U.S. PATENT DOCUMENTS** *EXAMINER FILING DATE DOCUMENT NUMBER DATE CLASS SUBCLASS NAME INITIAL IF APPROPRIATE **FOREIGN PATENT DOCUMENTS** TRANSLATION DOCUMENT NUMBER DATE COUNTRY CLASS SUBCLASS YES NO OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) Basili, V., et al., "Understanding and Prediciting the Process of Software Maintenance Releases," 18th International Conference on Software Engineering (ICSE'96), arch 25-29, 1996, p. 464 (Abstract) Fenton, N.E., et al., "A Critique of Software Defect Prediction Models," IEEE Transactions on Software Engineering; pp. 675-689 (Abstract) **EXAMINER** DATE CONSIDERED

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